# CY7C1021

## 64K x 16 Static RAM

### Features

- **High speed**
  - **— $t_{AA}$ = 12 ns**
- **CMOS for optimum speed/power**
- **Low active power**
  - **— 1320 mW (max.)**
- **Automatic power-down when deselected**
- **Independent Control of Upper and Lower bits**
- **Available in 44-pin TSOP II and 400-mil SOJ**

### Functional Description

The CY7C1021 is a high-performance CMOS static RAM organized as 65,536 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

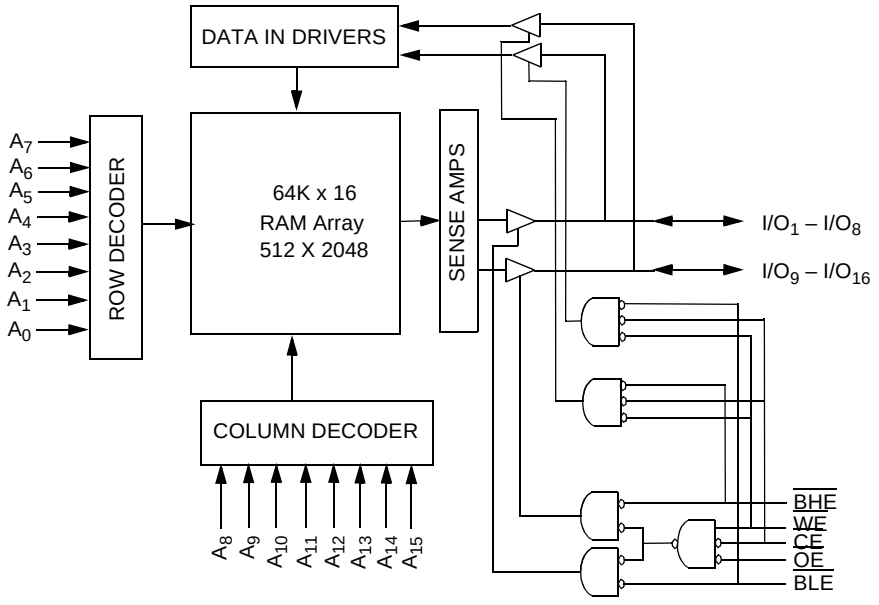
Writing to the device is accomplished by taking Chip Enable ($\overline{CE}$) and Write Enable ($\overline{WE}$) inputs LOW. If Byte Low Enable ($\overline{BLE}$) is LOW, then data from I/O pins ($I/O_1$ through $I/O_8$), is written into the location specified on the address pins ($A_0$ through $A_{15}$). If Byte High Enable ($\overline{BHE}$) is LOW, then data from I/O pins ($I/O_9$ through $I/O_{16}$) is written into the location specified on the address pins ($A_0$ through $A_{15}$).

Reading from the device is accomplished by taking Chip Enable ($\overline{CE}$) and Output Enable ($\overline{OE}$) LOW while forcing the write enable ($\overline{WE}$) HIGH. If Byte Low Enable ($\overline{BLE}$) is LOW, then data from the memory location specified by the address pins will appear on $I/O_1$ to $I/O_8$. If Byte High Enable ($\overline{BHE}$) is LOW, then data from memory will appear on $I/O_9$ to $I/O_{16}$. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins ($I/O_1$ through $I/O_{16}$) are placed in a high-impedance state when the device is deselected ($\overline{CE}$ HIGH), the outputs are disabled ($\overline{OE}$ HIGH), the $\overline{BHE}$ and $\overline{BLE}$ are disabled ($\overline{BHE}$, $\overline{BLE}$ HIGH), or during a write operation ($\overline{CE}$ LOW, and $\overline{WE}$ LOW).

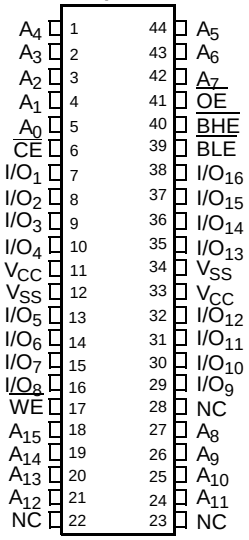
The CY7C1021 is available in standard 44-pin TSOP Type II and 400-mil-wide SOJ packages.

### Logic Block Diagram




### Pin Configuration

**SOJ / TSOP II**
**Top View**




1021-2

### Selection Guide

| | | 7C1021-10 | 7C1021-12 | 7C1021-15 | 7C1021-20 |
|---|---|---|---|---|---|
| Maximum Access Time (ns) | | 10 | 12 | 15 | 20 |
| Maximum Operating Current (mA) | Commercial | 220 | 220 | 220 | 220 |
| Maximum CMOS Standby Current (mA) | Commercial | 5 | 5 | 5 | 5 |
| | L | 0.5 | 0.5 | 0.5 | 0.5 |

Shaded areas contain preliminary information.

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....–65°C to +150°C

Ambient Temperature with Power Applied.....–55°C to +125°C

Supply Voltage on $V_{CC}$ to Relative GND[1] .... –0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State[1].....–0.5V to $V_{CC}$+0.5V

DC Input Voltage[1] .....–0.5V to $V_{CC}$+0.5V

Current into Outputs (LOW) ..... 20 mA

Static Discharge Voltage .....>2001V (per MIL-STD-883, Method 3015)

Latch-Up Current.....>200 mA

## Operating Range

| Range | Ambient Temperature[2] | $V_{CC}$ |
|---|---|---|
| Commercial | 0°C to +70°C | 5V ± 10% |
| Industrial | –40°C to +85°C | 5V ± 10% |

## Electrical Characteristics Over the Operating Range

| Parameter | Description | Test Conditions | | 7C1021-10 | | 7C1021-12 | | 7C1021-15 | | 7C1021-20 | | Unit |
|---|---|---|---|---|---|---|---|---|---|---|---|---|
| | | | | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | |
| $V_{OH}$ | Output HIGH Voltage | $V_{CC}$ = Min., $I_{OH}$ = –4.0 mA | | 2.4 | | 2.4 | | 2.4 | | 2.4 | | V |
| $V_{OL}$ | Output LOW Voltage | $V_{CC}$ = Min., $I_{OL}$ = 8.0 mA | | | 0.4 | | 0.4 | | 0.4 | | 0.4 | V |
| $V_{IH}$ | Input HIGH Voltage | | | 2.2 | 6.0 | 2.2 | 6.0 | 2.2 | 6.0 | 2.2 | 6.0 | V |
| $V_{IL}$ | Input LOW Voltage[1] | | | –0.5 | 0.8 | –0.5 | 0.8 | –0.3 | 0.8 | –0.3 | 0.8 | V |
| $I_{IX}$ | Input Load Current | GND ≤ $V_I$ ≤ $V_{CC}$ | | –1 | +1 | –1 | +1 | –1 | +1 | –1 | +1 | µA |
| $I_{OZ}$ | Output Leakage Current | GND ≤ $V_I$ ≤ $V_{CC}$, Output Disabled | | –1 | +1 | –1 | +1 | –5 | +5 | –5 | +5 | µA |
| $I_{OS}$ | Output Short Circuit Current[3] | $V_{CC}$ = Max., $V_{OUT}$ = GND | | | –300 | | –300 | | –300 | | –300 | mA |
| $I_{CC}$ | $V_{CC}$ Operating Supply Current | $V_{CC}$ = Max., $I_{OUT}$ = 0 mA, f = $f_{MAX}$ = $1/t_{RC}$ | | | 220 | | 220 | | 220 | | 200 | mA |
| $I_{SB1}$ | Automatic CE Power-Down Current —TTL Inputs | Max. $V_{CC}$, $\overline{CE}$ ≥ $V_{IH}$ $V_{IN}$ ≥ $V_{IH}$ or $V_{IN}$ ≤ $V_{IL}$, f = $f_{MAX}$ | | | 40 | | 40 | | 40 | | 40 | mA |
| $I_{SB2}$ | Automatic CE Power-Down Current —CMOS Inputs | Max. $V_{CC}$, $\overline{CE}$ ≥ $V_{CC}$ – 0.3V, $V_{IN}$ ≥ $V_{CC}$ – 0.3V, or $V_{IN}$ ≤ 0.3V, f=0 | | | 5 | | 5 | | 5 | | 5 | mA |
| | | | L | | 0.5 | | 0.5 | | 0.5 | | 0.5 | mA |

Shaded areas contain preliminary information.

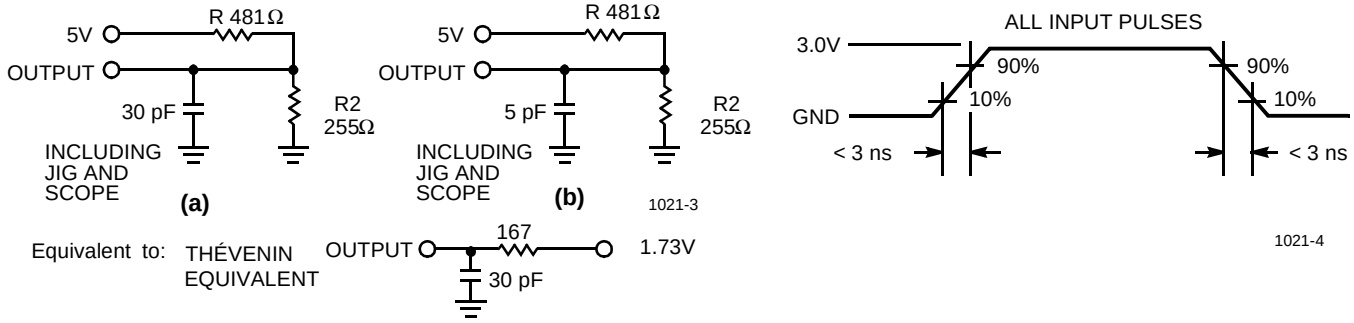
## Capacitance[4]

| Parameter | Description | Test Conditions | Max. | Unit |
|---|---|---|---|---|
| $C_{IN}$ | Input Capacitance | $T_A$ = 25°C, f = 1 MHz, $V_{CC}$ = 5.0V | 8 | pF |
| $C_{OUT}$ | Output Capacitance | | 8 | pF |

**Notes:**

1. $V_{IL}$ (min.) = –2.0V for pulse durations of less than 20 ns.
2. $T_A$ is the case temperature.
3. Not more than one output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds.
4. Tested initially and after any design or process changes that may affect these parameters.

## AC Test Loads and Waveforms




## Switching Characteristics[5] Over the Operating Range

| Parameter | Description | 7C1021-10 | | 7C1021-12 | | 7C1021-15 | | 7C1021-20 | | Unit |
|---|---|---|---|---|---|---|---|---|---|---|
| | | Min. | Max. | Min. | Max. | Min. | Max. | Min. | Max. | |
| **READ CYCLE** | | | | | | | | | | |
| $t_{RC}$ | Read Cycle Time | 10 | | 12 | | 15 | | 20 | | ns |
| $t_{AA}$ | Address to Data Valid | | 10 | | 12 | | 15 | | 20 | ns |
| $t_{OHA}$ | Data Hold from Address Change | 3 | | 3 | | 3 | | 3 | | ns |
| $t_{ACE}$ | $\overline{CE}$ LOW to Data Valid | | 10 | | 12 | | 15 | | 20 | ns |
| $t_{DOE}$ | $\overline{OE}$ LOW to Data Valid | | 5 | | 6 | | 7 | | 9 | ns |
| $t_{LZOE}$ | $\overline{OE}$ LOW to Low Z[6] | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{HZOE}$ | $\overline{OE}$ HIGH to High Z[6, 7] | | 5 | | 6 | | 7 | | 9 | ns |
| $t_{LZCE}$ | $\overline{CE}$ LOW to Low Z[6] | 3 | | 3 | | 3 | | 3 | | ns |
| $t_{HZCE}$ | $\overline{CE}$ HIGH to High Z[6, 7] | | 5 | | 6 | | 7 | | 9 | ns |
| $t_{PU}$ | $\overline{CE}$ LOW to Power-Up | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{PD}$ | $\overline{CE}$ HIGH to Power-Down | | 10 | | 12 | | 15 | | 20 | ns |
| $t_{DBE}$ | Byte Enable to Data Valid | | 5 | | 6 | | 7 | | 9 | ns |
| $t_{LZBE}$ | Byte Enable to Low Z | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{HZBE}$ | Byte Disable to High Z | | 5 | | 6 | | 7 | | 9 | ns |
| **WRITE CYCLE**[8] | | | | | | | | | | |
| $t_{WC}$ | Write Cycle Time | 10 | | 12 | | 15 | | 20 | | ns |
| $t_{SCE}$ | $\overline{CE}$ LOW to Write End | 8 | | 9 | | 10 | | 12 | | ns |
| $t_{AW}$ | Address Set-Up to Write End | 7 | | 8 | | 10 | | 12 | | ns |
| $t_{HA}$ | Address Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{SA}$ | Address Set-Up to Write Start | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{PWE}$ | $\overline{WE}$ Pulse Width | 7 | | 8 | | 10 | | 12 | | ns |
| $t_{SD}$ | Data Set-Up to Write End | 5 | | 6 | | 8 | | 10 | | ns |
| $t_{HD}$ | Data Hold from Write End | 0 | | 0 | | 0 | | 0 | | ns |
| $t_{LZWE}$ | $\overline{WE}$ HIGH to Low Z[6] | 3 | | 3 | | 3 | | 3 | | ns |
| $t_{HZWE}$ | $\overline{WE}$ LOW to High Z[6, 7] | | 5 | | 6 | | 7 | | 9 | ns |
| $t_{BW}$ | Byte Enable to End of Write | 7 | | 8 | | 9 | | 12 | | ns |

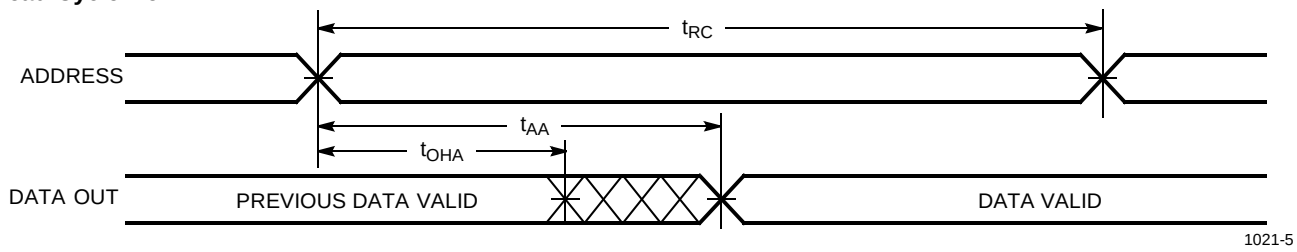
Shaded areas contain preliminary information.

**Notes:**

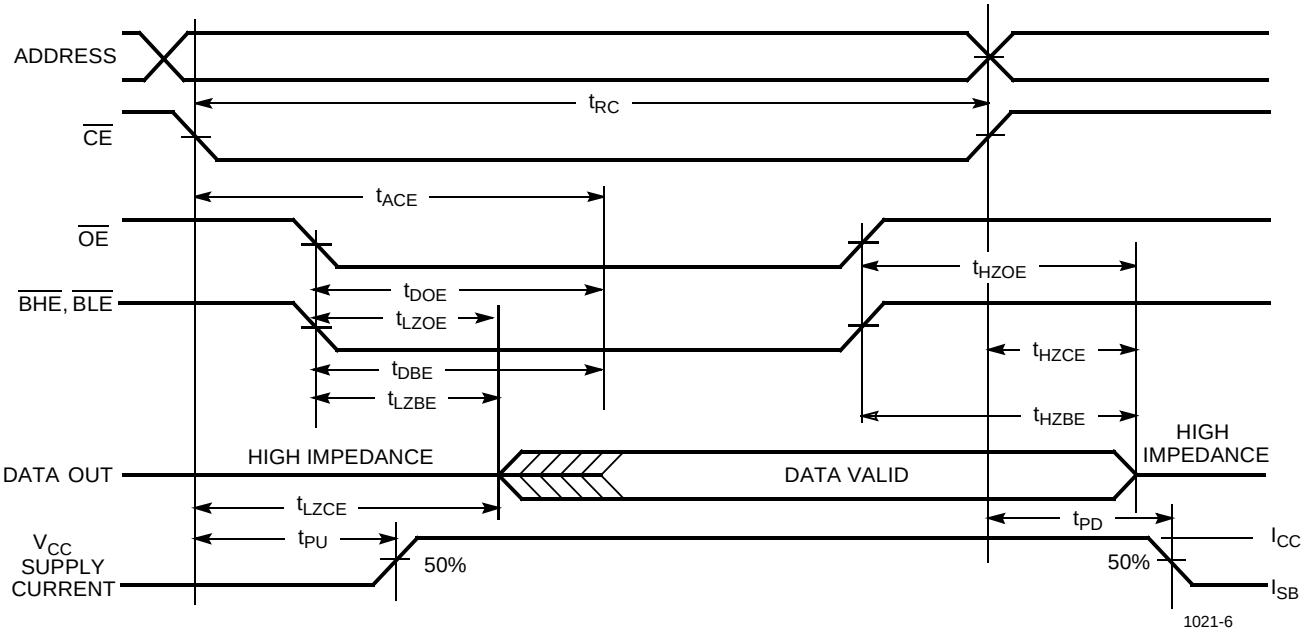
5. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified $I_{OL}/I_{OH}$ and 30-pF load capacitance.
6. At any given temperature and voltage condition, $t_{HZCE}$ is less than $t_{LZCE}$, $t_{HZOE}$ is less than $t_{LZOE}$, and $t_{HZWE}$ is less than $t_{LZWE}$ for any given device.
7. $t_{HZOE}$, $t_{HZBE}$, $t_{HZCE}$, and $t_{HZWE}$ are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
8. The internal write time of the memory is defined by the overlap of $\overline{CE}$ LOW, $\overline{WE}$ LOW and $\overline{BHE}$ / $\overline{BLE}$ LOW. $\overline{CE}$, $\overline{WE}$ and $\overline{BHE}$ / $\overline{BLE}$ must be LOW to initiate a write, and the transition of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

## Switching Waveforms

**Read Cycle No. 1**[9, 10]



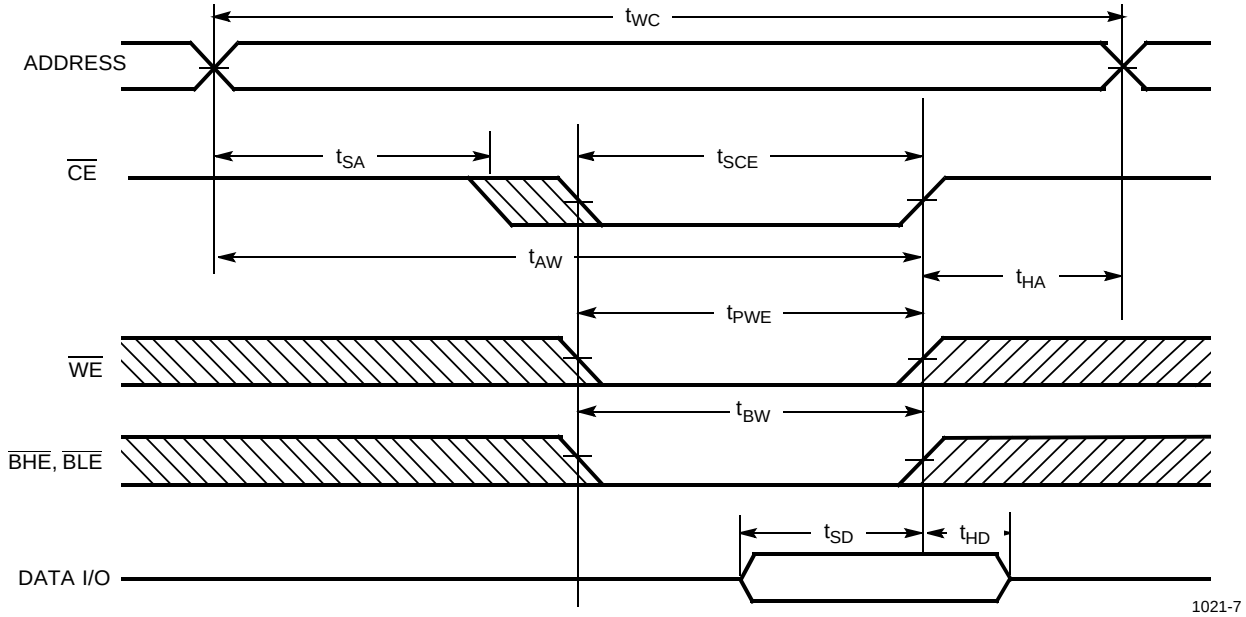

**Read Cycle No. 2 ($\overline{OE}$ Controlled)**[10, 11]



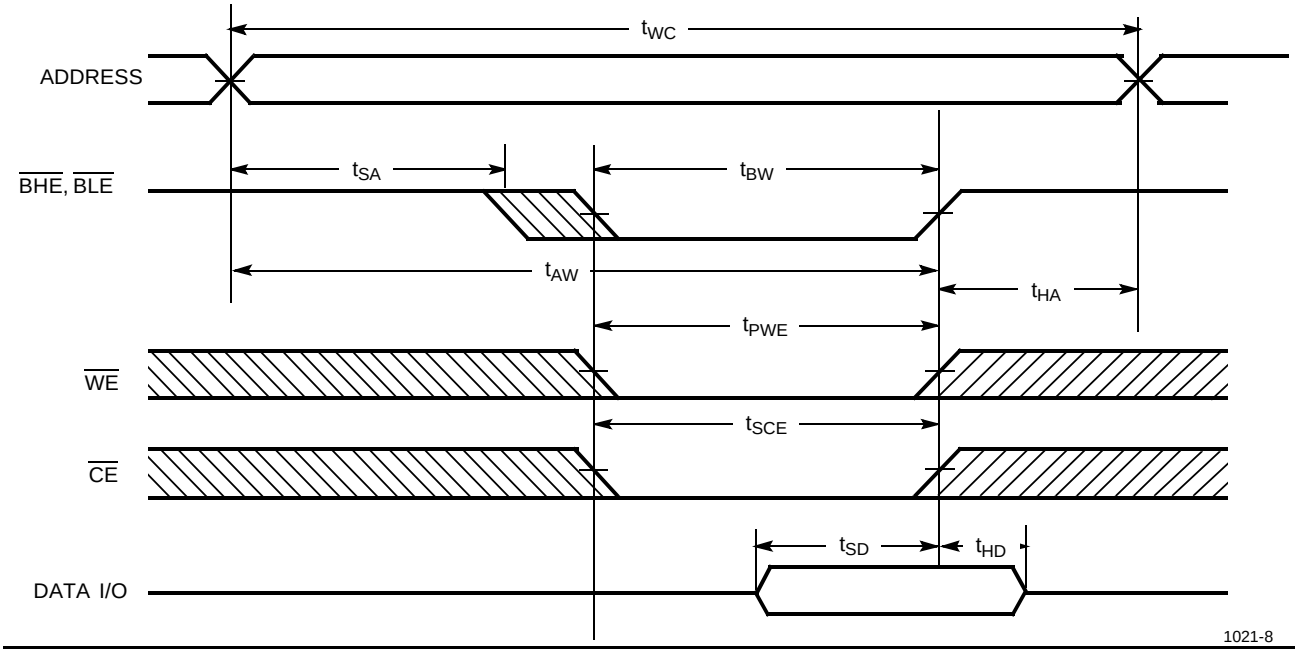

**Notes:**
9. Device is continuously selected. $\overline{OE}$, $\overline{CE}$, $\overline{BHE}$ and/or $\overline{BHE}$ = $V_{IL}$.
10. $\overline{WE}$ is HIGH for read cycle.
11. Address valid prior to or coincident with $\overline{CE}$ transition LOW.

## Switching Waveforms (continued)

### Write Cycle No. 1 ($\overline{CE}$ Controlled) [12, 13]



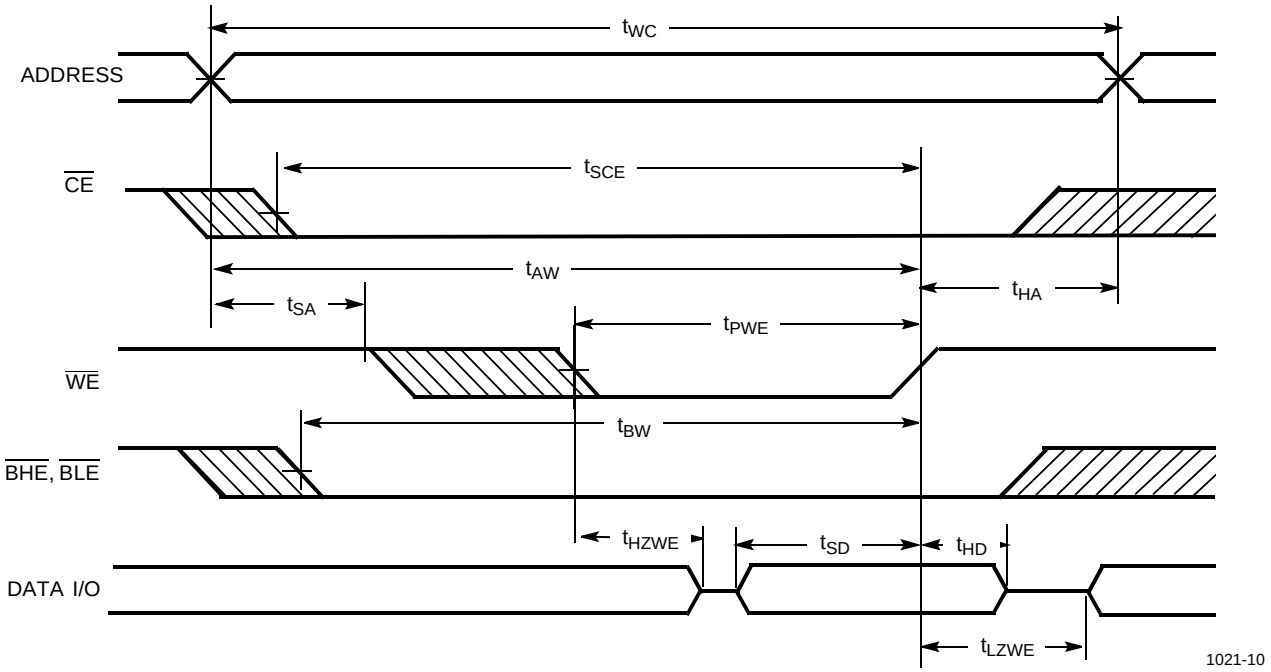

### Write Cycle No. 2 ($\overline{BLE}$ or $\overline{BHE}$ Controlled)




**Notes:**
12. Data I/O is high impedance if $\overline{OE}$ or $\overline{BHE}$ and/or $\overline{BLE}$= $V_{IH}$.
13. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ going HIGH, the output remains in a high-impedance state.

## Switching Waveforms (continued)

**Write Cycle No. 3 ($\overline{WE}$ Controlled, LOW)**




## Truth Table

| CE | OE | WE | BLE | BHE | $I/O_1$–$I/O_8$ | $I/O_9$–$I/O_{16}$ | Mode | Power |
|---|---|---|---|---|---|---|---|---|
| H | X | X | X | X | High Z | High Z | Power-Down | Standby ($I_{SB}$) |
| L | L | H | L | L | Data Out | Data Out | Read - All bits | Active ($I_{CC}$) |
| | | | L | H | Data Out | High Z | Read - Lower bits only | Active ($I_{CC}$) |
| | | | H | L | High Z | Data Out | Read - Upper bits only | Active ($I_{CC}$) |
| L | X | L | L | L | Data In | Data In | Write - All bits | Active ($I_{CC}$) |
| | | | L | H | Data In | High Z | Write - Lower bits only | Active ($I_{CC}$) |
| | | | H | L | High Z | Data In | Write - Upper bits only | Active ($I_{CC}$) |
| L | H | H | X | X | High Z | High Z | Selected, Outputs Disabled | Active ($I_{CC}$) |
| L | X | X | H | H | High Z | High Z | Selected, Outputs Disabled | Active ($I_{CC}$) |

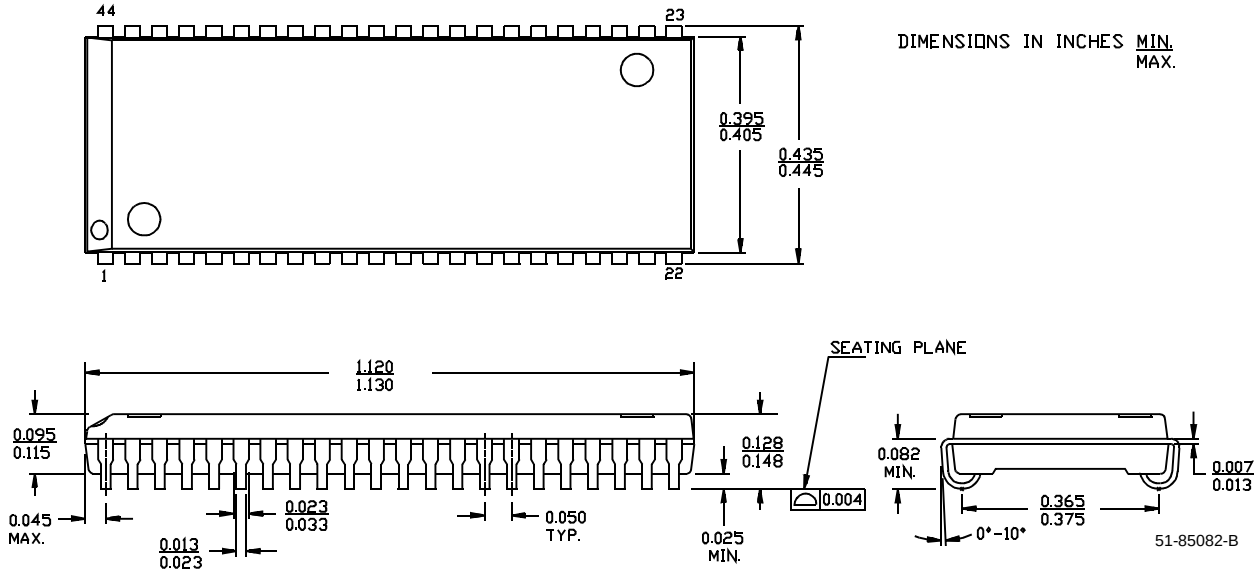
## Ordering Information

| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|---|---|---|---|---|
| 10 | CY7C1021-10VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
| | CY7C1021-10ZC | Z44 | 44-Lead TSOP Type II | Commercial |
| | CY7C1021L-10ZC | Z44 | 44-Lead TSOP Type II | Commercial |
| 12 | CY7C1021-12VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
| | CY7C1021-12VI | V34 | 44-Lead (400-Mil) Molded SOJ | Industrial |
| | CY7C1021-12ZC | Z44 | 44-Lead TSOP Type II | Commercial |
| 15 | CY7C1021-15VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
| | CY7C1021-15VI | V34 | 44-Lead (400-Mil) Molded SOJ | Industrial |
| | CY7C1021-15ZC | Z44 | 44-Lead TSOP Type II | Commercial |
| | CY7C1021-15ZI | Z44 | 44-Lead TSOP Type II | Industrial |
| | CY7C1021L-15ZC | Z44 | 44-Lead TSOP Type II | Commercial |
| 20 | CY7C1021-20VC | V34 | 44-Lead (400-Mil) Molded SOJ | Commercial |
| | CY7C1021-20ZC | Z44 | 44-Lead TSOP Type II | Commercial |

Shaded areas contain preliminary information.

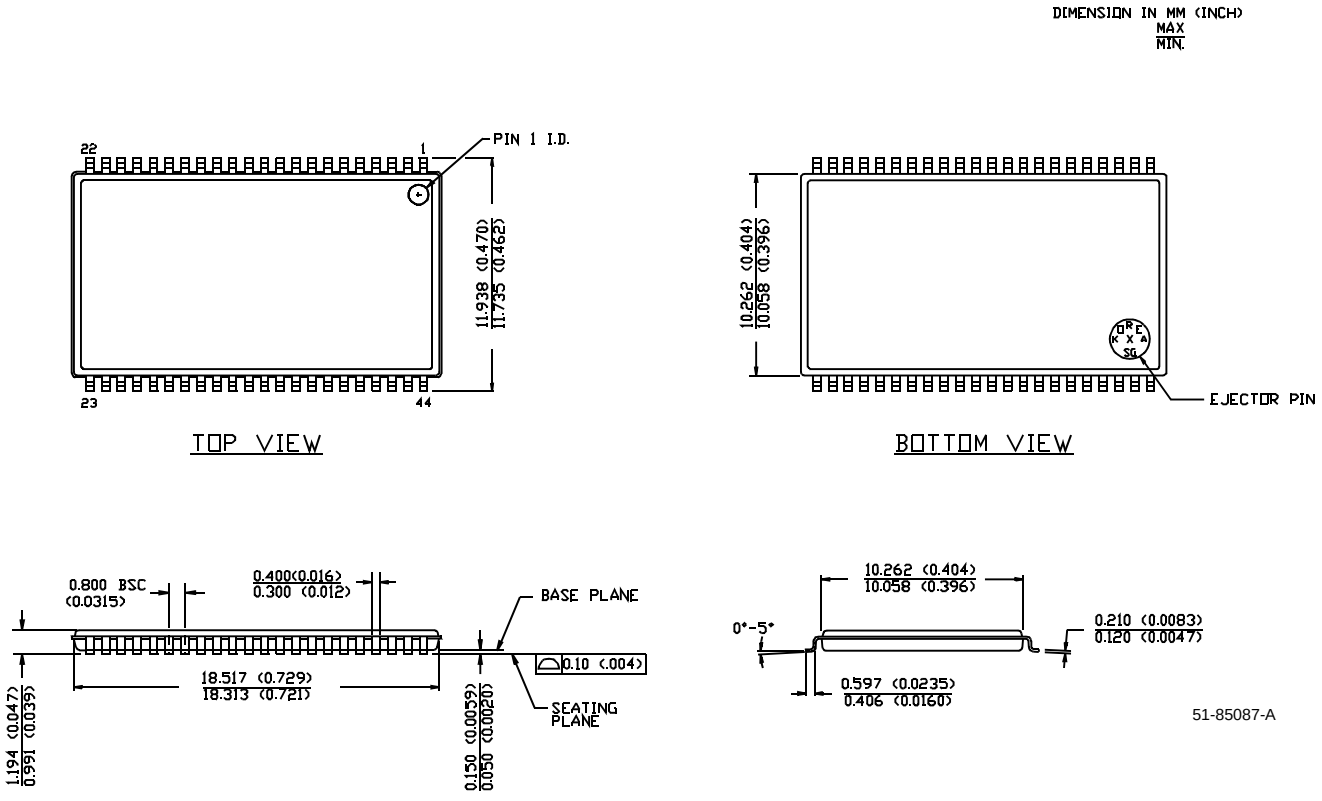
## Package Diagrams

**44-Lead (400-Mil) Molded SOJ V34**



## Package Diagrams (continued)

**44-Pin TSOP II Z44**



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